

CLAIMS

1. A probe station for probing a test device, said probe station comprising:

5 (a) a chuck for supporting said test device;

(b) a plurality of electrically conductive members, each electrically isolated from, and at least partially enclosing said surface; and

10 (c) a selector member having a plurality of positions, one said position electrically isolating said electrically conductive members from each other and another said position electrically interconnecting one said conductive member with at least one other said conductive member.

15 2. The probe station of claim 1 having only two said conductive members.

3. The probe station of claim 1 including an outer conductive member at least partially surrounding at least one other said conductive member.